## Notice of References Cited

Application/Control No. 10/692,127	Applicant(s)/Pater Reexamination CHEN ET AL.			
Examiner	Art Unit			
Alan S. Chou	2151	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0099837	07-2002	Oe et al.	709/229
*	В	US-2004/0064572	04-2004	Yamaguchi et al.	709/229
*	С	US-2007/0038765	02-2007	Dunn, Melissa W.	709/229 ·
*	D	US-2003/0145094	07-2003	Staamann et al.	709/229
*	Е	US-2002/0143963	10-2002	Converse et al.	709/229
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
1	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

<del></del>	1	
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	•
	v	
	w	
	×	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.